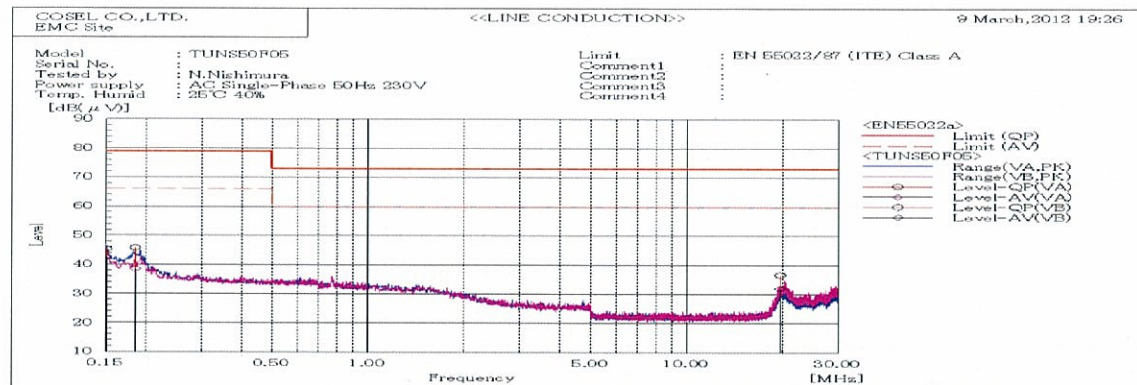
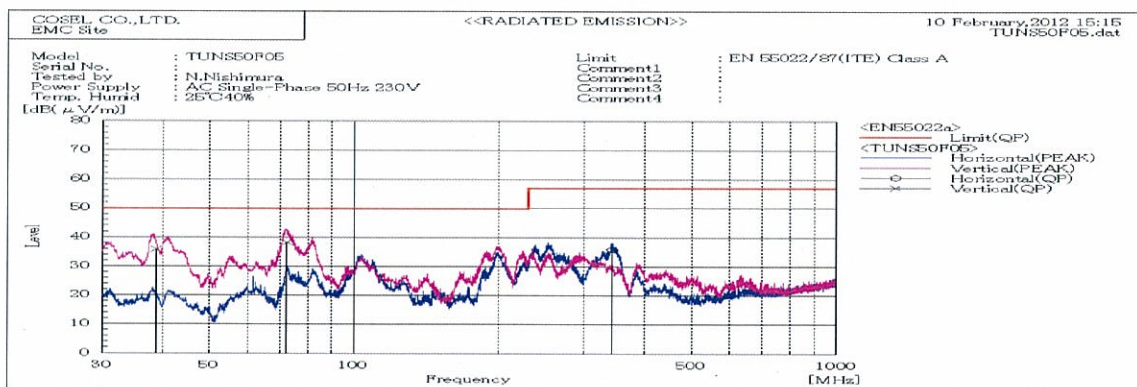


DATA SHEET			Date	17-Apr-12
Model	TUNS50F05		Temp.	25 degreeC
Test	EMI		Humid.	40 %RH
	Line conduction & Radiated emission		Tested by	N.Nishimura



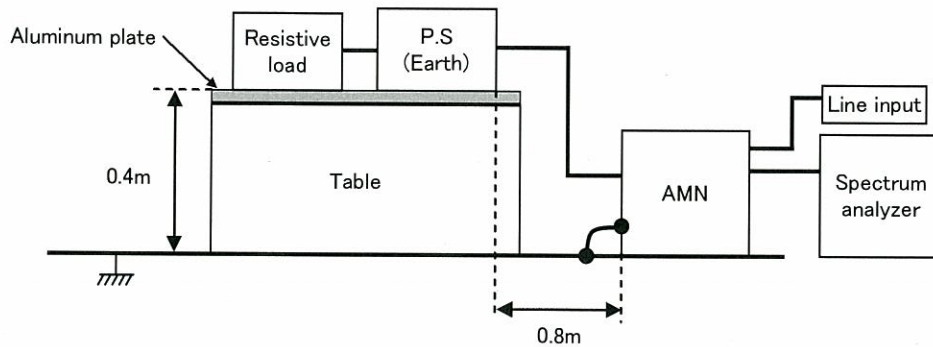
Frequency MHz	Line Phase	Reading dB(uV)		Factor dB	Level dB(uV)		Limit dB(uV)		Margin dB		Pass/ Fail
		QP	AV		QP	AV	QP	AV	QP	AV	
0.15061	VA	35.2	32.3	10.2	45.4	42.5	79	66	33.6	23.5	Pass
0.18539	VA	35.5	28.3	10.2	45.7	38.5	79	66	33.3	27.5	Pass
19.6611	VB	25.8	21.2	10.9	36.7	32.1	73	60	36.3	27.9	Pass



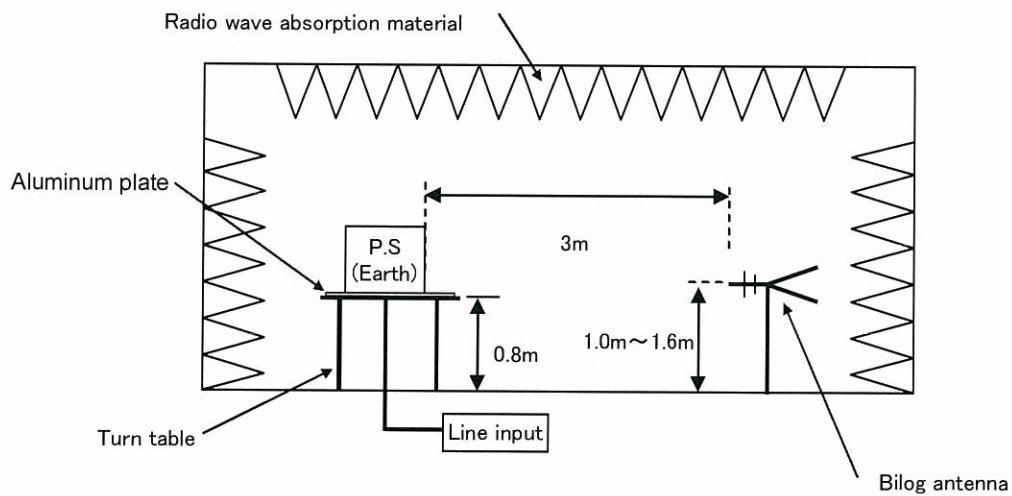
Frequency MHz	Polarization	Stability	Reading dB(uV)	Space Loss dB	Level dB(mW)	Limit dB(mW)	Margi n dB	Height cm	Angle deg	Pass/ Fail
			QP		QP	QP	QP			
38.747	V	Stable	51.3	-15.5	35.8	50	14.2	103	35	Pass
72.539	V	Stable	58.5	-20.3	38.2	50	11.8	122	6	Pass
342.504	H	Stable	49.4	-13.6	35.8	57	21.2	126	9	Pass

DATA SHEET		Date	17-Apr-12
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	N.Nishimura

1. Line conduction



2. Radiated emission

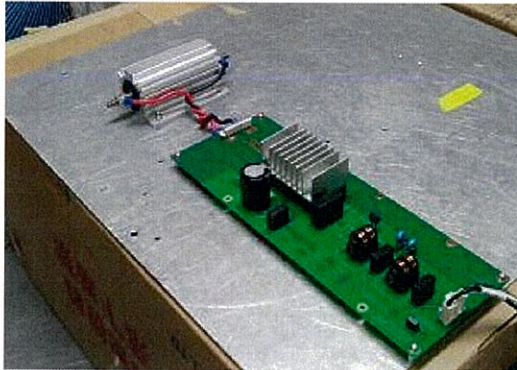


Test: EMI

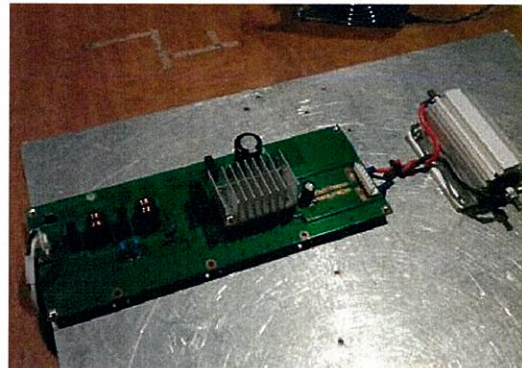
Model Name: TUNS50F Series

○ Photographs of Test Set-Up

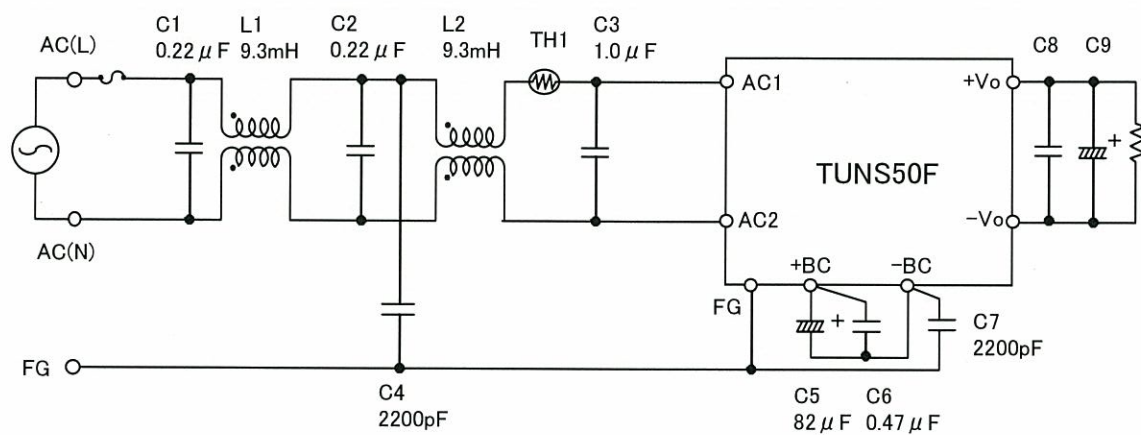
LINE CONDUCTION



RADIATED EMISSION



○ Test circuit



L1,L2 : SS11VL-R10093(NEC TOKIN)

TH1 : 5D2-08(SEMITEC)

C8 : TUNS50F05 10 μF
 TUNS50F12 10 μF
 TUNS50F24 4.7 μF

C9 : TUNS50F05 2200 μF
 TUNS50F12 470 μF
 TUNS50F24 220 μF